

# FDS4072N3

# 40V N-Channel PowerTrench® MOSFET

## **General Description**

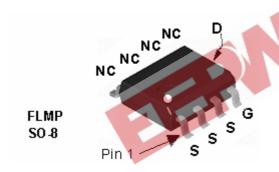
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{\text{DS(ON)}}$  in a small package.

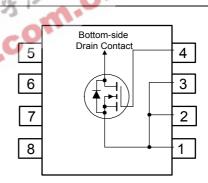
### **Applications**

- · Synchronous rectifier
- DC/DC converter

#### **Features**

- 12.4 A, 40 V  $R_{DS(ON)} = 12 \text{ m}\Omega$  @  $V_{GS} = 4.5 \text{ V}$   $R_{DS(ON)} = 10 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize ON})}$
- · High power and current handling capability
- Fast switching
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		40	V
V <sub>GSS</sub>	Gate-Source Voltage		± 12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	12.4	А
	- Pulsed		60	
P <sub>D</sub>	Power Dissipation	(Note 1a)	3.0	W
		(Note 1b)	1.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tem	perature Range	-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.5	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4072N3	FDS4072N3	13"	12mm	2500 units

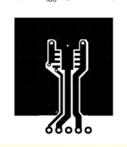
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (No	te 2)	1		I.	I .
E <sub>AS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 20V$ , $I_D = 12.4$ A			200	mJ
I <sub>AS</sub>	Drain-Source Avalanche Current				12.4	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	40			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		38		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 32 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μА
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
$I_{GSSR}$	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}$ , $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)			_		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1	1.3	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C	2_	-4.5		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 12.4 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 13.7 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 12.4 \text{ A}, T_J = 125^{\circ}\text{C}$	·n	9.7 8.5 14.7	12 10 20	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	30			Α
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 12.4 \text{ A}$		84		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 20 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		4299		pF
Coss	Output Capacitance	f = 1.0 MHz		351		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			149		pF
Switchin	g Characteristics (Note 2)					_
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 20 \text{ V}, \qquad I_{D} = 1 \text{ A},$		20	36	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		12	22	ns
$t_{\text{d(off)}} \\$	Turn-Off Delay Time			52	83	ns
t <sub>f</sub>	Turn-Off Fall Time			18	32	ns
$Q_g$	Total Gate Charge	$V_{DS} = 20 \text{ V}, \qquad I_{D} = 12.4 \text{ A},$		33	46	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 4.5 V		7.8		nC
$Q_{gd}$	Gate-Drain Charge			8.1		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
l <sub>s</sub>	Maximum Continuous Drain-Source	e Diode Forward Current			2.5	Α
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 2.5 \text{ A}  \text{(Note 2)}$		0.7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 12.4 \text{ A},$		30		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_{t} = 100 \text{ A/}\mu\text{s}$		90		nC

## **Electrical Characteristics**

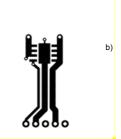
T<sub>A</sub> = 25°C unless otherwise noted

#### Notes:

1. R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



40°C/W when mounted on a 1in² pad of 2 oz copper



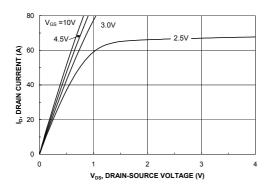
85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

**2.** Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%



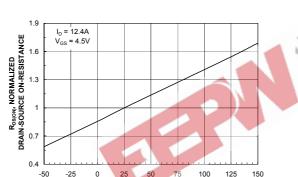
# **Typical Characteristics**



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Figure 1. On-Region Characteristics.



T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

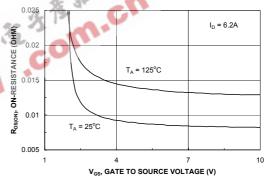


Figure 3. On-Resistance Variation withTemperature.

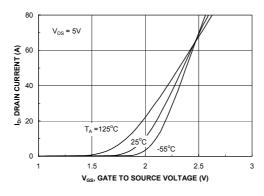


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

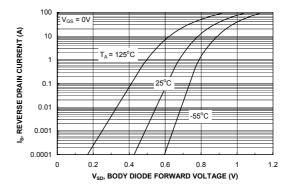
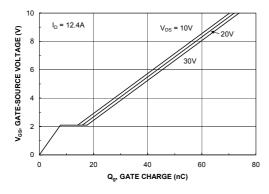


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



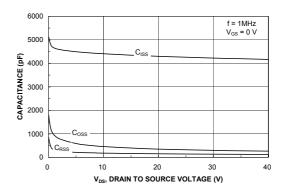


Figure 7. Gate Charge Characteristics.

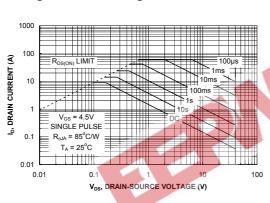


Figure 8. Capacitance Characteristics.

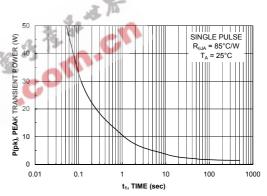


Figure 9. Maximum Safe Operating Area.



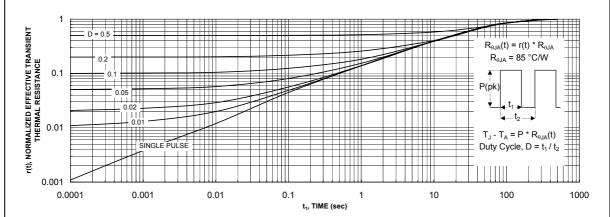


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

# **Dimensional Outline and Pad Layout** -(0.65) (2.36)DRAIN TERMINAL -0.75 MIN (0.67)5 (2.36)2.80 MIN 7.40 DRAIN 2.80 MIN TERMINAL 8 0.70 BOTTOM VIEW 1.50 MIN 4.90±0.10-В PATTERN RECOMMENDATION 3.90±0.10 SEE DETAIL A \_0.51 0.35 (0.34)**⊕** 0.127**M** B A 1.27 6.00±0.20 NOTES: UNLESS OTHERWISE SPECIFIED ALL DIMENSIONS ARE IN MILLIMETERS. STANDARD LEAD FINISH: 20-80 MICROINCHES NICKEL/ 6 MICROINCHES MAX. PALLADIUM AND GOLD FLASH. NO JEDEC REGISTERED REFERENCE AS OF MARCH 2, 2000. -0.50 X 45° GAGE PLANE 1.60 MAX 0.90 0.50 SEATING PLANE **--** (1.04) **-**DETAIL A SCALE: 24:1

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